

# OptiMOS™ 2 + OptiMOS™-P 2 Small Signal Transistor

#### **Features**

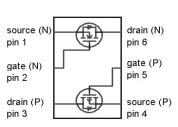
- · Complementary P + N channel
- · Enhancement mode
- Super Logic level (2.5V rated)
- · Avalanche rated
- · Qualified according to AEC Q101
- · 100% lead-free; RoHS compliant
- · Halogen-free according to IEC61249-2-21





#### **Product Summary**

		Р	N	
V <sub>DS</sub>		-20	20	V
$R_{\mathrm{DS(on),max}}$	V <sub>GS</sub> =±4.5 V	1200	350	mΩ
	V <sub>GS</sub> =±2.5 V	2100	600	
I <sub>D</sub>		-0.53	0.95	Α



# 6 5 4

PG-SOT-363

Туре	Package	Tape and Reel Information	Marking	Lead Free	Packing
BSD235C	PG-SOT-363	H6327: 3000 pcs / reel	sPH	Yes	Non dry

**Maximum ratings,** at  $T_j$ =25 °C, unless otherwise specified <sup>1)</sup>

Parameter	Symbol	Conditions	Value		Unit
			Р	N	
Continuous drain current	ID	T <sub>A</sub> =25 °C	-0.53	0.95	А
		T <sub>A</sub> =70 °C	-0.46	0.76	
Pulsed drain current	I <sub>D,pulse</sub>	T <sub>A</sub> =25 °C	-2.1	3.8	
Avalanche energy, single pulse	E <sub>AS</sub>	P: $I_D$ =-0.53 A, N: $I_D$ =0.95 A, $R_{GS}$ =25 $\Omega$	1.4	1.6	mJ
Gate source voltage	$V_{GS}$		±12		V
Power dissipation	P <sub>tot</sub>	T <sub>A</sub> =25 °C	0.5		W
Operating and storage temperature	$T_{\rm j}, T_{\rm stg}$		-55 150		°C
ESD class		JESD22-A114-HBM	0 (<250V)		°C
Soldering temperature	T <sub>solder</sub>		260		°C
IEC climatic category; DIN IEC 68-1	_		55/1	50/56	

<sup>1)</sup> Remark: only one of both transistors active



resistance

Transconductance

Parameter		Symbol	Conditions	Values			Unit
				min.	typ.	max.	
Thermal characteristics							
Thermal resistance, junction - ambient	P N	$R_{thJA}$	minimal footprint <sup>2)</sup>	-	-	250	K/W
Electrical characteristics, at $T_j$ =	25 °C	C, unless	otherwise specified				
Static characteristics							
Drain-source breakdown voltage	Р	$V_{(BR)DSS}$	V <sub>GS</sub> =0 V, I <sub>D</sub> =-250 μA	-	-	-20	V
	N		V <sub>GS</sub> =0 V, I <sub>D</sub> =250 μA	20	-	-	
Gate threshold voltage	Р	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -1.5 \mu{\rm A}$	-1.2	-0.9	-0.6	
	N		$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 1.6 \ \mu {\rm A}$	0.7	0.95	1.2	
Zero gate voltage drain current	Р	I <sub>DSS</sub>	$V_{\rm DS}$ =-20 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	-	-	-1	μΑ
	N		V <sub>DS</sub> =20 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	-	-	1	
	Р		V <sub>DS</sub> =-20 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =150 °C	-	-	-100	
	N		V <sub>DS</sub> =20 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =150 °C	-	-	100	
Gate-source leakage current	P N	.I <sub>GSS</sub>	V <sub>GS</sub> =±12 V, V <sub>DS</sub> =0 V	ı	-	±100	nA
Drain-source on-state	Р	R <sub>DS(on)</sub>	V <sub>GS</sub> =-2.5 V, I <sub>D</sub> =-0.17 A	-	1221	2100	mΩ

Ν

Ν

 $P g_{fs}$ 

Ν

I<sub>D</sub>=-0.46 A

 $I_{\rm D}$ =0.76 A

 $V_{\rm GS}$ =2.5 V,  $I_{\rm D}$ =0.29 A

 $V_{GS}$ =4.5 V,  $I_{D}$ =0.95 A

 $|V_{\rm DS}| > 2|I_{\rm D}|R_{\rm DS(on)max}$ 

 $|V_{\rm DS}| > 2|I_{\rm D}|R_{\rm DS(on)max}$ 

 $V_{\rm GS}$ =-4.5V,  $I_{\rm D}$ =-

0.53 A

415

745

266

0.7

2

600

1200

350

S

 $<sup>^{2)}</sup>$  Performed on  $40 mm^2$  FR4 PCB. The traces are 1mm wide,  $70\,\mu m$  thick and 20mm long; they are present on both sides of the PCB



Parameter	Symb		Conditions		Values		Unit
				min.	typ.	max.	
Dynamic characteristics							
Input capacitance	Р	$C_{\rm iss}$		-	37	-	pF
	N		N -0 W	-	47	-	
Output capacitance	Р	$C_{\rm oss}$	V <sub>GS</sub> =0 V, P: V <sub>DS</sub> =-10 V,	-	17	-	
	N		N: V <sub>DS</sub> = 10 V, f=1 MHz	-	24	-	
Reverse transfer capacitance	Р	C <sub>rss</sub>	7 – 1 1011 12	-	14	-	
	N			-	3	-	1
Turn-on delay time	Р	$t_{d(on)}$		-	3.8	-	ns
	N	1		-	3.8	-	
Rise time	P: $V_{DD}$ =-10 V, $V_{GS}$ =-4.5 V, $R_{G}$ =6 Ω, $I_{D}$ =-0.53 A		-	5.0	-		
			-	3.6	-		
Turn-off delay time	Р	$t_{\text{d(off)}}$ N: $V_{\text{DD}}$ =10 V,	-	5.1	-		
	N		$V_{\rm GS}$ =4.5 V, $R_{\rm G}$ =6 $\Omega$ , $I_{\rm D}$ =0.95 A	-	4.5	-	
Fall time	Р	$t_{f}$	75 в.бв 71	-	3.2	-	
	N			-	1.2	-	
Gate Charge Characteristics	•	•					•
Gate to source charge	Р	Q <sub>gs</sub>			-0.09	-	nC
Gate to drain charge		Q <sub>gd</sub>	V <sub>DD</sub> =-10 V, I <sub>D</sub> =-0.53 A,	-	-0.2	1	
Switching charge		$Q_g$	$V_{\rm GS}$ =0 to -4.5 V	-	-0.4	-	
Gate plateau voltage		$V_{\rm plateau}$	1	-	-2.4	-	
Gate to source charge	N	Q <sub>gs</sub>		-	0.11	-	1
Gate to drain charge		$Q_{\rm gd}$ $Q_{\rm g}$	$V_{\rm DD}$ =16 V, $I_{\rm D}$ =0.95 A, $V_{\rm GS}$ =0 to 4.5 V	-	0.09	-	
Switching charge				-	0.34	-	
Gate plateau voltage		V <sub>plateau</sub>		-	2.4	-	1



Parameter		Symbol	Conditions	Values			Unit
				min.	typ.	max.	
Reverse Diode							
Diode continuous forward current	Р	Is		-	-	-0.42	А
	N	1	T -25 °C			0.5	
Diode pulse current	Р	I <sub>S,pulse</sub>	T <sub>C</sub> =25 °C	_	-	-2.1	
	N			-	-	3.8	
Diode forward voltage	Р	V <sub>SD</sub>	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =-0.53 A, $T_{\rm j}$ =25 °C	-	-1	-1.2	V
	N		V <sub>GS</sub> =0 V, I <sub>F</sub> =0.95 A, T <sub>j</sub> =25 °C	-	0.9	1.1	
Reverse recovery time	Р	t <sub>rr</sub>		-	7.6	-	ns
	N		V <sub>R</sub> =±10 V, I <sub>F</sub> =I <sub>S</sub> ,	-	5.2	-	
Reverse recovery charge	Р	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/µs	-	1.1	-	nC
	Ν			-	0.97	-	



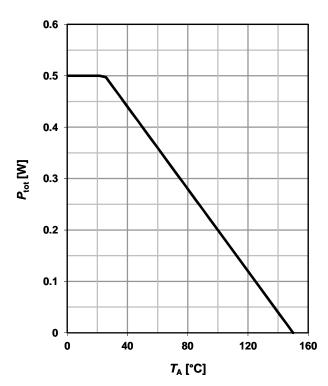
#### 1 Power dissipation (P)

# $P_{\text{tot}} = f(T_A)$

# 0.6 0.5 0.4 0.2 0.1 0 40 80 120 160 T<sub>A</sub> [°C]

# 2 Power dissipation (N)

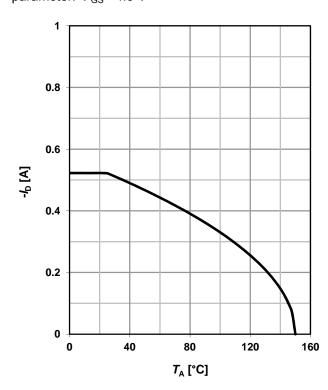
$$P_{\text{tot}} = f(T_A)$$



# 3 Drain current (P)

 $I_{D}=f(T_{A})$ 

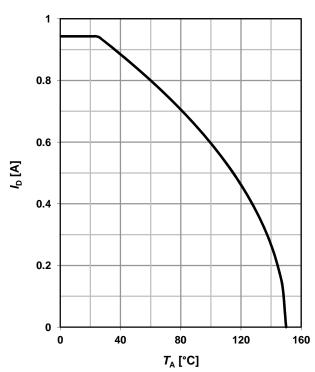
parameter: V<sub>GS</sub>≤-4.5 V



# 4 Drain current (N)

 $I_D = f(T_A)$ 

parameter: V<sub>GS</sub>≥4.5 V

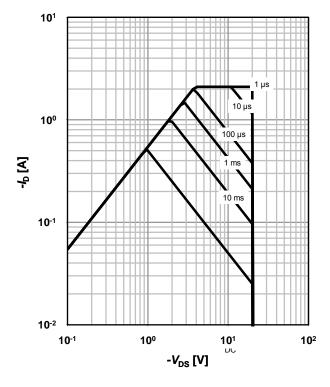




#### 5 Safe operating area (P)

 $I_{D}=f(V_{DS}); T_{A}=25 \text{ °C}; D=0$ 

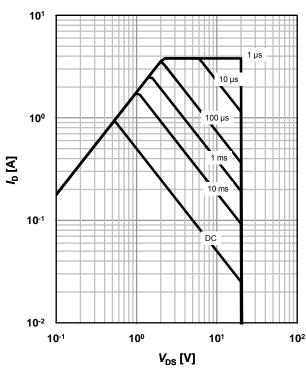
parameter:  $t_p$ 



#### 6 Safe operating area (N)

 $I_D=f(V_{DS}); T_A=25 \text{ °C}; D=0$ 

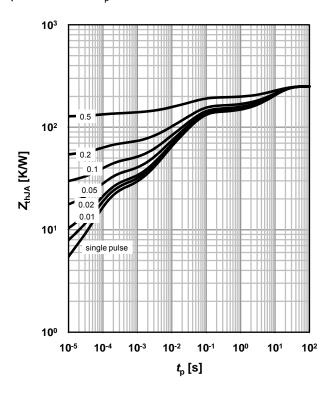
parameter:  $t_p$ 



#### 7 Max. transient thermal impedance (P)

 $Z_{\text{thJA}}$ =f( $t_{p}$ )

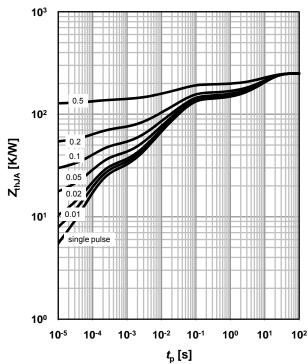
parameter:  $D=t_p/T$ 



#### 8 Max. transient thermal impedance (N)

 $Z_{\rm thJA}$ =f( $t_{\rm p}$ )

parameter:  $D = t_p/T$ 

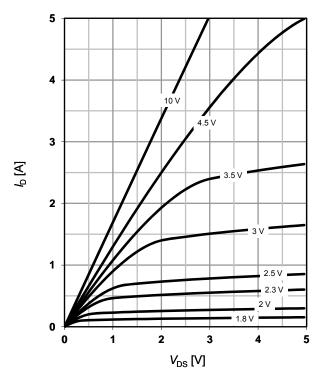




#### 9 Typ. output characteristics (P)

 $I_D = f(V_{DS}); T_i = 25 °C$ 

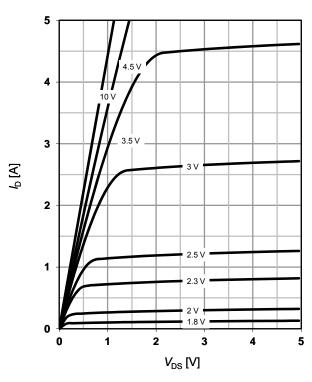
parameter:  $V_{\rm GS}$ 



#### 10 Typ. output characteristics (N)

 $I_D = f(V_{DS}); T_j = 25 °C$ 

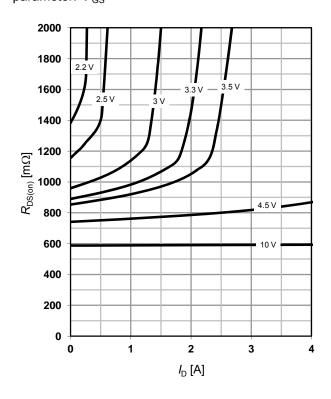
parameter:  $V_{\rm GS}$ 



#### 11 Typ. drain-source on resistance (P)

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

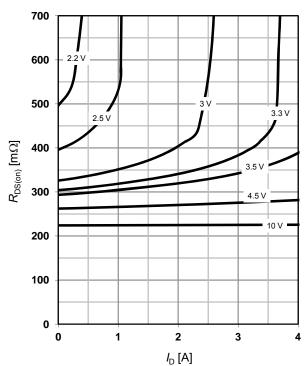
parameter: V<sub>GS</sub>



#### 12 Typ. drain-source on resistance (N)

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

parameter: V<sub>GS</sub>

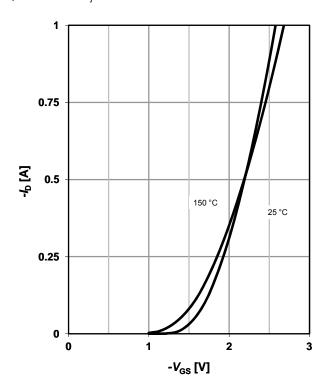




#### 13 Typ. transfer characteristics (P)

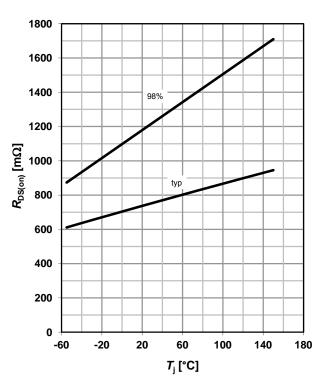
 $I_{D}$ =f( $V_{GS}$ );  $|V_{DS}|$ >2 |  $I_{D}|R_{DS(on)max}$ 

parameter: T<sub>j</sub>



#### 15 Drain-source on-state resistance (P)

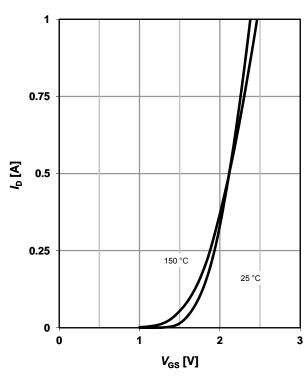
 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =-0.53 A;  $V_{GS}$ =-4.5 V



#### 14 Typ. transfer characteristics (N)

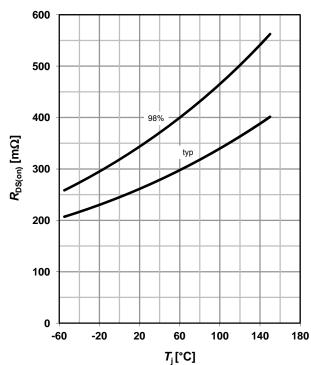
 $I_D$ =f( $V_{GS}$ );  $|V_{DS}|$ >2  $|I_D|R_{DS(on)max}$ 

parameter: T<sub>j</sub>



#### 16 Drain-source on-state resistance (N)

 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =0.95 A;  $V_{GS}$ =4.5 V



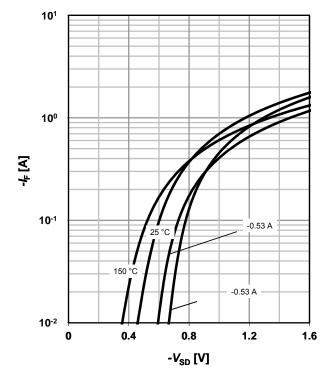
10<sup>3</sup>



#### 21 Forward characteristics of reverse diode (P)

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

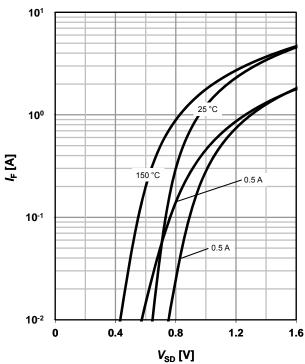
parameter: T<sub>j</sub>



#### 22 Forward characteristics of reverse diode (N)

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter: T<sub>j</sub>



#### 23 Avalanche characteristics (P)

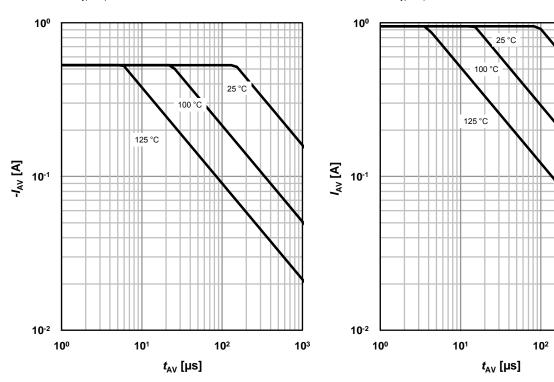
 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

parameter: T<sub>i(start)</sub>

#### 24 Avalanche characteristics (N)

 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

parameter:  $T_{j(start)}$ 



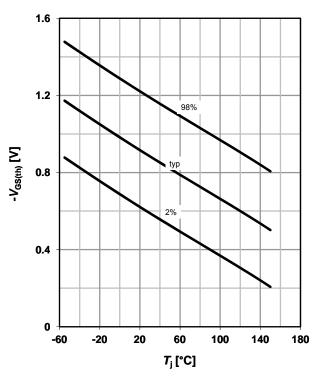


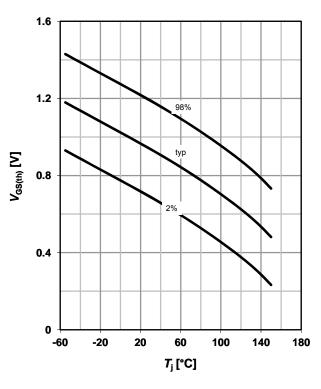
#### 17 Typ. gate threshold voltage (P)

#### $V_{GS(th)}$ =f( $T_i$ ); $V_{GS}$ = $V_{DS}$ ; $I_D$ =-1.5 $\mu$ A

#### 18 Typ. gate threshold voltage (N)

$$V_{GS(th)}=f(T_i); V_{GS}=V_{DS}; I_D=1.6 \mu A$$



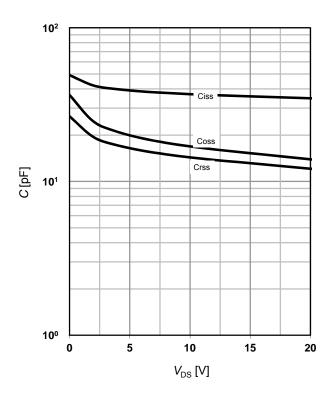


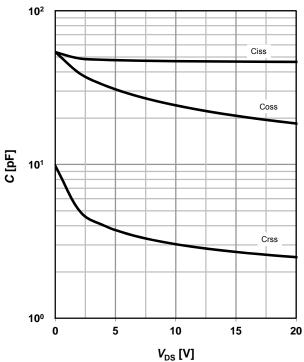
# 19 Typ. capacitances (P)

 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 

# 20 Typ. capacitances (N)

$$C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$$



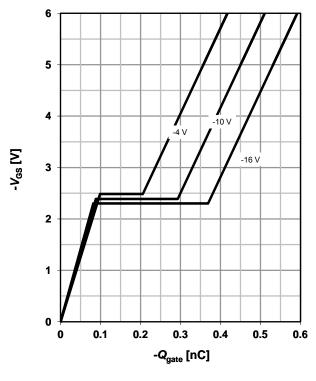




#### 25 Typ. gate charge (P)

 $V_{\rm GS}$ =f( $Q_{\rm gate}$ );  $I_{\rm D}$ =-0.53 A pulsed

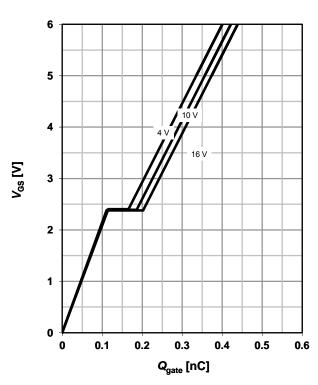
parameter:  $V_{\rm DD}$ 



#### 26 Typ. gate charge (N)

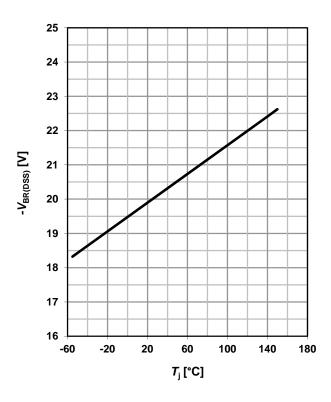
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =0.95 A pulsed

parameter: V<sub>DD</sub>



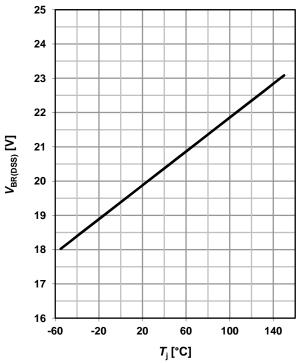
#### 27 Drain-source breakdown voltage (P)

 $V_{BR(DSS)}$ = $f(T_j)$ ;  $I_D$ =-250  $\mu A$ 



#### 28 Drain-source breakdown voltage (N)

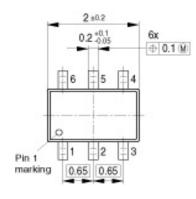
 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =250  $\mu$ A

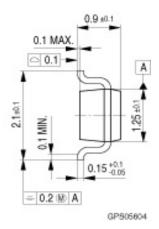




#### **SOT-363**

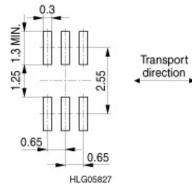
#### Package Outline:

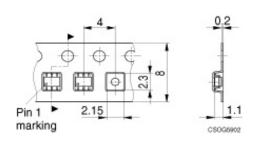




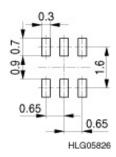
#### **Footprint:**

### Packing:





#### Reflow soldering:



#### Dimensions in mm



Published by Infineon Technologies AG 81726 Munich, Germany © 2008 Infineon Technologies AG All Rights Reserved.

#### Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

#### Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

#### Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.